


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/006,669	OGAWA ET AL.	
	Examiner	Art Unit	
	Gabriel L. Chu	2114	

ISSUE CLASSIFICATION									
ORIGINAL			CROSS REFERENCE(S)						
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
714	8	714	710						
INTERNATIONAL CLASSIFICATION									
G06F	11/00								
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	/								
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<i>Reilly</i> (Assistant Examiner)	<i>5/26/05</i> (Date)	<i>Robert Beausoliel</i> ROBERT BEAUSOLIEL SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2100 (Primary Examiner)	Total Claims Allowed: <i>5</i>
<i>Delella</i> (Legal Instruments Examiner)	<i>6/2/05</i> (Date)		O.G. Print Claim(s) <i>1</i>

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original		
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